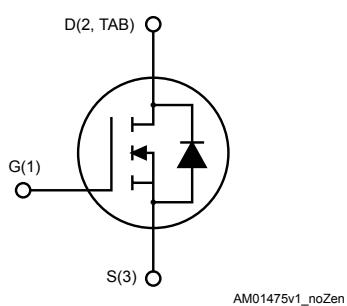


N-channel 500 V, 0.7 Ω typ., 7.5 A, MDmesh™ Power MOSFET in a DPAK package

Features



Order code	V _{DS}	R _{D(on)} max.	I _D
STD5NM50T4	500 V	0.8 Ω	7.5 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

This N-channel Power MOSFET is developed using STMicroelectronics' revolutionary MDmesh™ technology, which associates the multiple drain process with the company's PowerMESH™ horizontal layout. This device offers extremely low on-resistance, high dv/dt and excellent avalanche characteristics. Utilizing ST's proprietary strip technique, this Power MOSFET boasts an overall dynamic performance which is superior to similar products on the market.

Product status link

[STD5NM50T4](#)

Product summary

Order code	STD5NM50T4
Marking	D5NM50
Package	DPAK
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Gate-source voltage	500	V
V_{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	500	V
V_{GS}	Gate- source voltage	± 30	V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	7.5	A
I_D	Drain current (continuous) at $T_C = 100^\circ\text{C}$	4.7	
$I_{DM}^{(1)}$	Drain current (pulsed)	30	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	100	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_j	Operating junction temperature range		

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 5 \text{ A}$, $di/dt \leq 400 \text{ A}/\mu\text{s}$, $V_{DS \ peak} < V_{(BR)DSS}$, $V_{DD} = 400 \text{ V}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	1.25	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb	50	

1. When mounted on a 1-inch² FR-4, 2 oz Cu board

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_{jmax})	2.5	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	300	mJ

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified).

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	500			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 500 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 500 \text{ V}, T_C = 125^\circ\text{C}^{(1)}$			10	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 30 \text{ V}$			± 100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$		0.7	0.8	Ω

1. Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	415	-	pF
C_{oss}	Output capacitance		-	88	-	pF
C_{rss}	Reverse transfer capacitance		-	12	-	pF
$C_{\text{oss eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ V to } 400 \text{ V}, V_{GS} = 0 \text{ V}$	-	50	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	3	-	Ω
Q_g	Total gate charge	$V_{DD} = 400 \text{ V}, I_D = 7.5 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$	-	13	-	nC
Q_{gs}	Gate-source charge	(see Figure 13. Test circuit for gate charge behavior)	-	5	-	nC
Q_{gd}	Gate-drain charge		-	6	-	nC

1. $C_{\text{oss eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$	Turn-on delay time	$V_{DD} = 250 \text{ V}, I_D = 2.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	16	-	ns
t_r	Rise time	(see Figure 12. Test circuit for resistive load switching times and Figure 17. Switching time waveform)	-	8	-	ns
$t_{d(V_{off})}$	Off-voltage rise time		-	14	-	ns
t_f	Fall time	$R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times and Figure 17. Switching time waveform)	-	6	-	ns
t_c	Cross-over time		-	13	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		7.5	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		30	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$, $I_{SD} = 7.5 \text{ A}$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$,	-	185		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	1.1		μC
I_{RRM}	Reverse recovery current	$I_{SD} = 5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	11.5		A
t_{rr}	Reverse recovery time	$I_{SD} = 5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$,	-	270		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	1.6		μC
I_{RRM}	Reverse recovery current	$I_{SD} = 5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	12		A

1. Pulse width is limited by safe operating area

2. Pulse test: pulse duration = 300 μs , duty cycle 1.5%

2.1

Electrical characteristics (curves)

Figure 1. Safe operating area

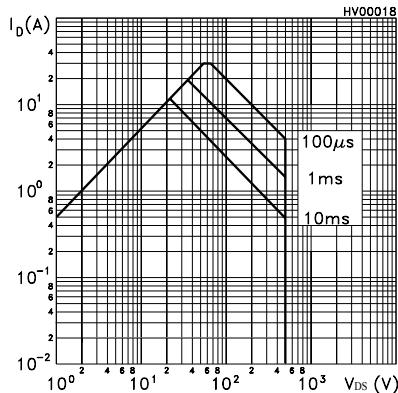


Figure 2. Thermal impedance

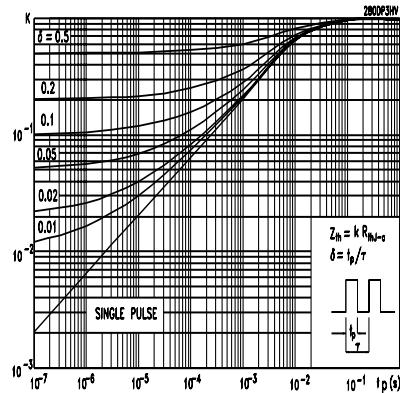


Figure 3. Output characteristics

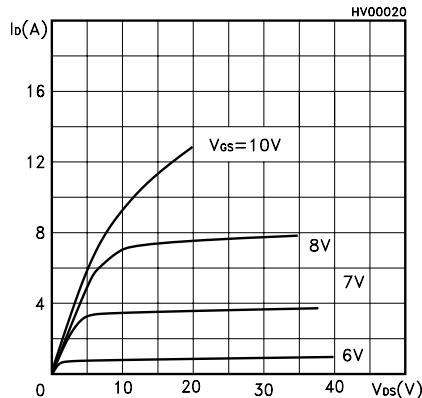


Figure 4. Transfer characteristics

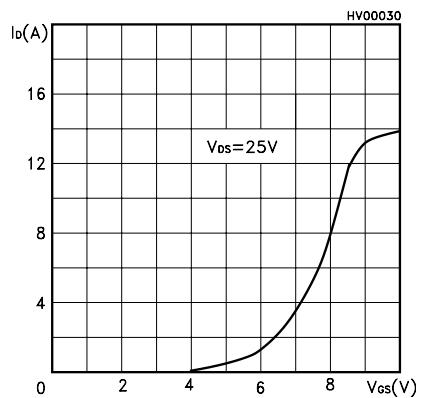


Figure 5. Normalized gate threshold voltage vs temperature

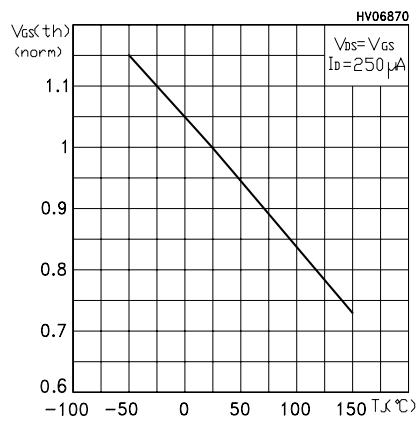


Figure 6. Normalized V_(BR)DSS vs temperature

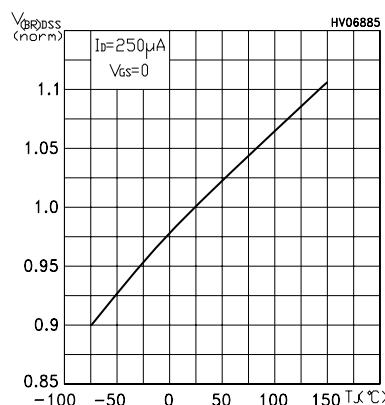
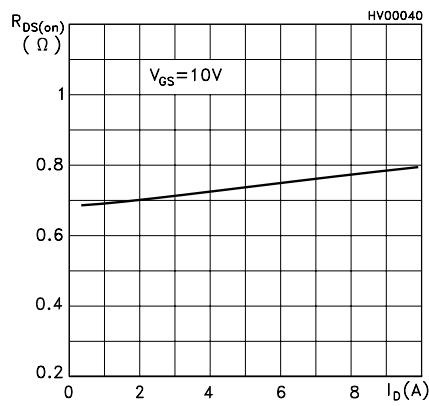
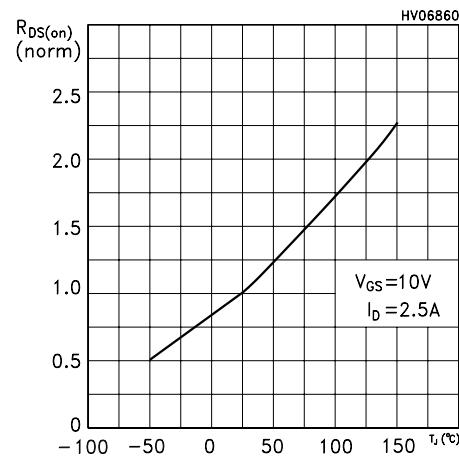
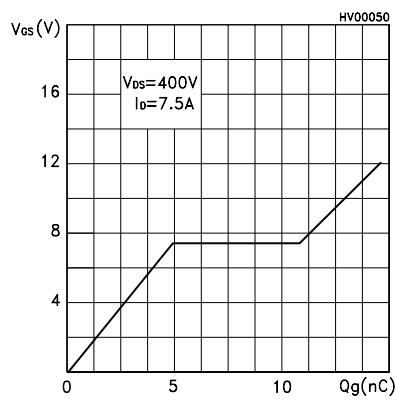
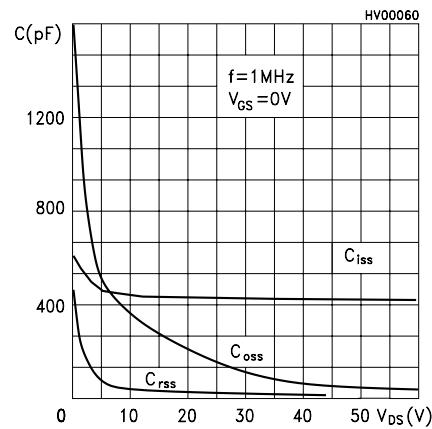
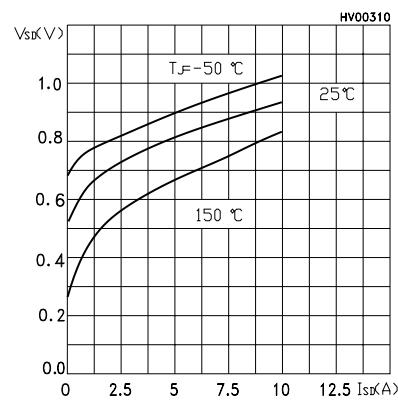
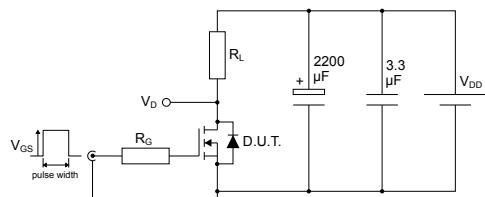


Figure 7. Static drain-source on-resistance

Figure 8. Normalized on-resistance vs temperature

Figure 9. Gate charge vs gate-source voltage

Figure 10. Capacitance variations

Figure 11. Source-drain diode forward characteristics


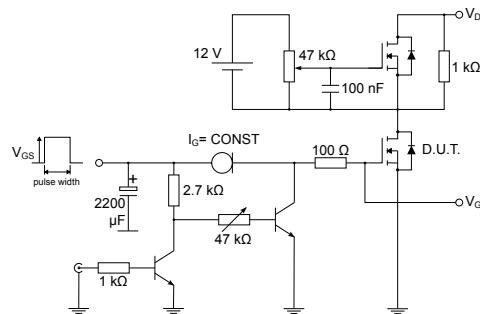
3 Test circuits

Figure 12. Test circuit for resistive load switching times



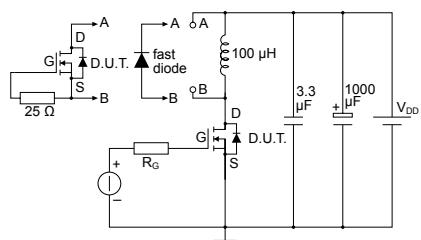
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Figure 13. Test circuit for gate charge behavior



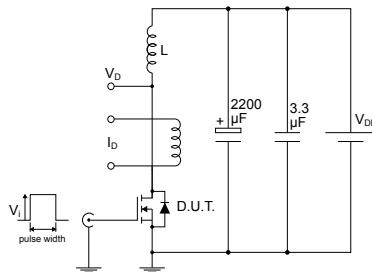
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Figure 14. Test circuit for inductive load switching and diode recovery times



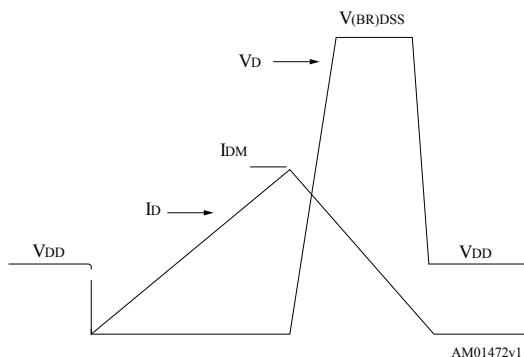
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Figure 15. Unclamped inductive load test circuit



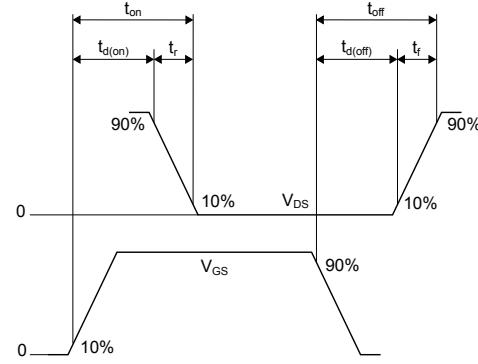
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Figure 16. Unclamped inductive waveform



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Figure 17. Switching time waveform



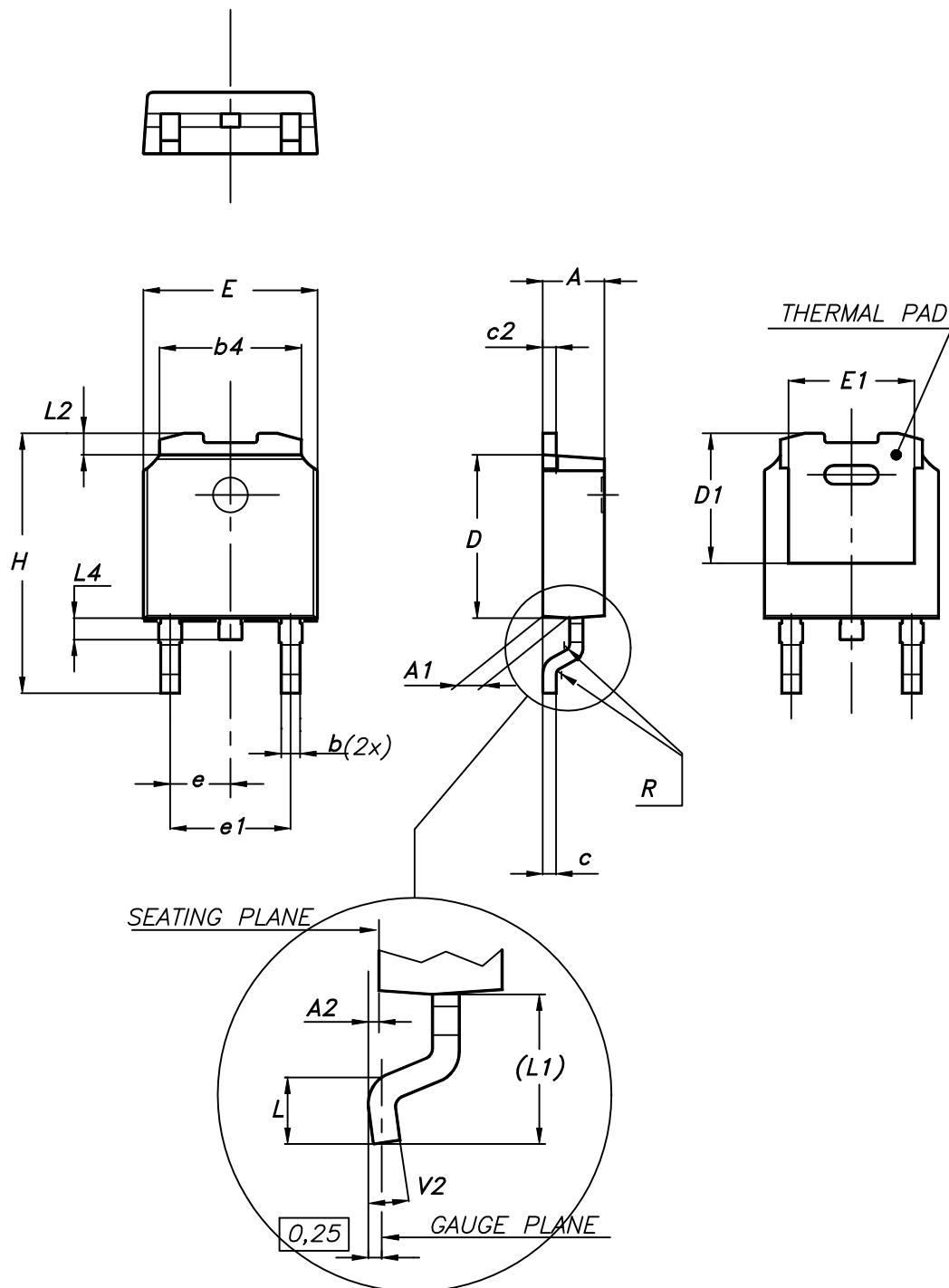
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4**Package information**

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 DPAK (TO-252) type A2 package information

Figure 18. DPAK (TO-252) type A2 package outline



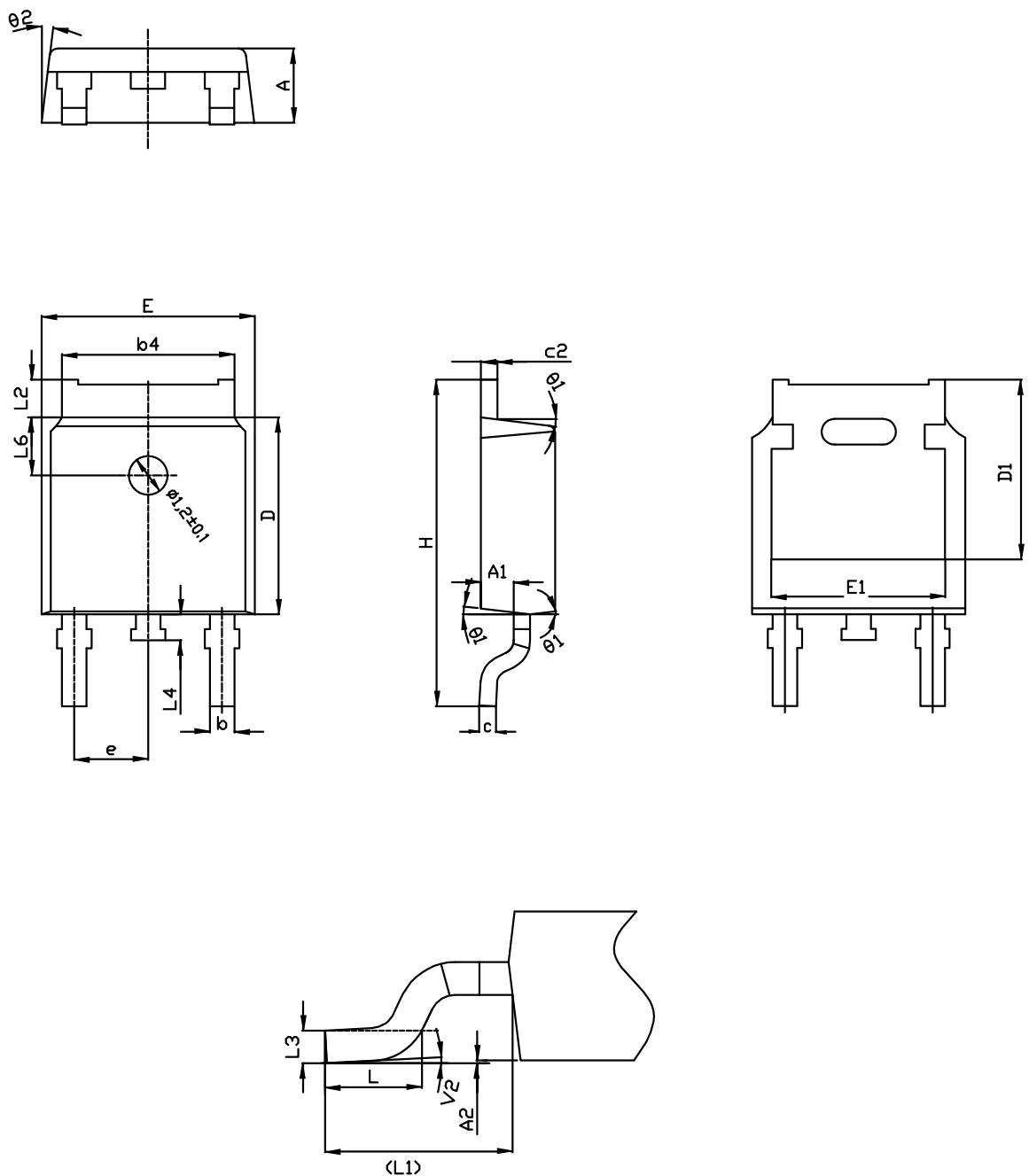
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Table 8. DPAK (TO-252) type A2 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1	4.95	5.10	5.25
E	6.40		6.60
E1	5.10	5.20	5.30
e	2.159	2.286	2.413
e1	4.445	4.572	4.699
H	9.35		10.10
L	1.00		1.50
L1	2.60	2.80	3.00
L2	0.65	0.80	0.95
L4	0.60		1.00
R		0.20	
V2	0°		8°

4.2 DPAK (TO-252) type C2 package information

Figure 19. DPAK (TO-252) type C2 package outline

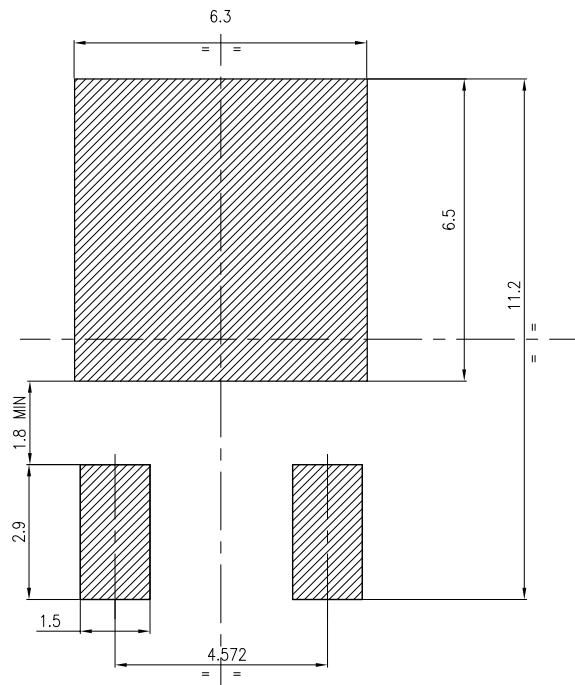


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Table 9. DPAK (TO-252) type C2 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.38
A1	0.90	1.01	1.10
A2	0.00		0.10
b	0.72		0.85
b4	5.13	5.33	5.46
c	0.47		0.60
c2	0.47		0.60
D	6.00	6.10	6.20
D1	5.10		5.60
E	6.50	6.60	6.70
E1	5.20		5.50
e	2.186	2.286	2.386
H	9.80	10.10	10.40
L	1.40	1.50	1.70
L1	2.90 REF		
L2	0.90		1.25
L3	0.51 BSC		
L4	0.60	0.80	1.00
L6	1.80 BSC		
θ1	5°	7°	9°
θ2	5°	7°	9°
V2	0°		8°

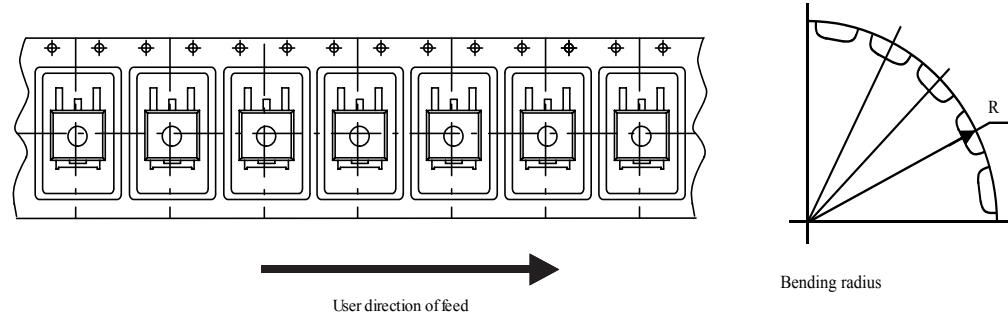
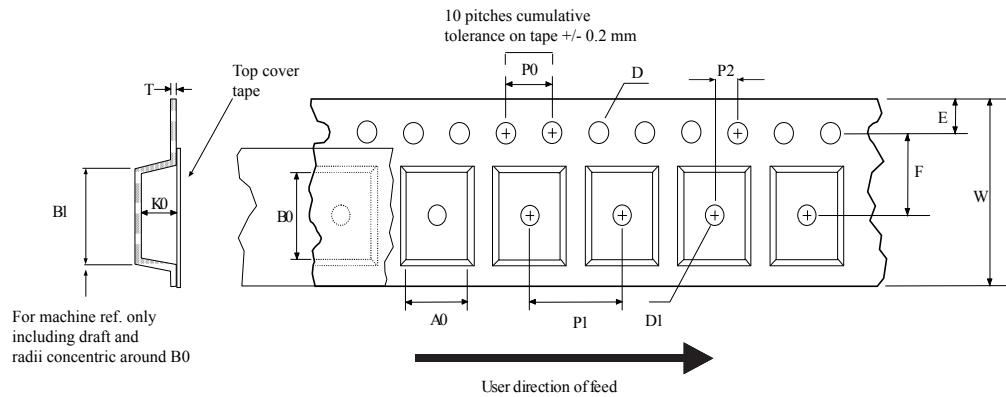
Figure 20. DPAK (TO-252) recommended footprint (dimensions are in mm)



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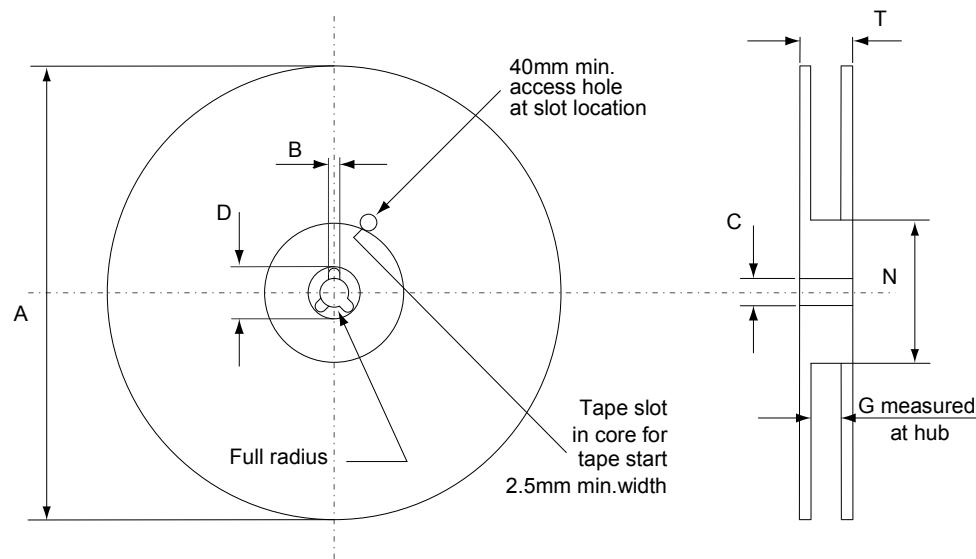
4.3 DPAK (TO-252) packing information

Figure 21. DPAK (TO-252) tape outline



Bending radius

AM08852v1

Figure 22. DPAK (TO-252) reel outline

AM06038v1

Table 10. DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

Revision history

Table 11. Document revision history

Date	Version	Changes
07-Sep-2018	11	<p>The part number STD5NM50-1 have been moved to a separate datasheet.</p> <p>Modified title, features, description and applications on cover page.</p> <p>Modified Table 2. Thermal data.</p> <p>Modified Section 2.1 Electrical characteristics (curves).</p> <p>Updated Section 3 Test circuits.</p> <p>Updated Section 4 Package information.</p> <p>Minor text changes.</p>

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